

Patent Abstracts of Japan

PUBLICATION NUMBER : 62223679
PUBLICATION DATE : 01-10-87

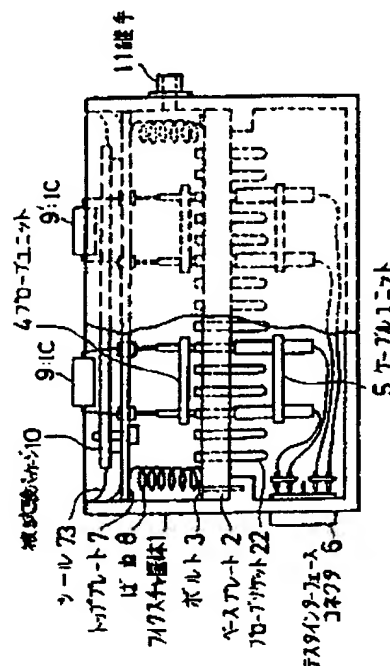
APPLICATION DATE : 25-03-86
APPLICATION NUMBER : 61066812

APPLICANT : NEC CORP;

INVENTOR : YOKOTA NORIO;

INT.CL. : G01R 31/28

TITLE : FIXTURE FOR IN-CIRCUIT TESTER



ABSTRACT : PURPOSE: To test various packages by one fixture by embedding probe sockets in the entire surface of a base plate and using a probe socket and a cable unit corresponding to each shape of a component.

CONSTITUTION: The base plate 2 is constituted by embedding probe sockets 22 in the entire surface of an insulation substrate at the same pitch with the standard grating of a package printed board to be tested, and fixed to a fixture housing 1 with a bolt 3. A probe unit 4, on the other hand, is inserted into an optional position on the top surface of the plate 2; and one end of a cable unit 5 is inserted into an optional position on the reverse surface of the plate 2 and the other end is inserted into an optional pin of a tester interface connector 6 fitted to the housing 11. A top plate 7 is holed over the plate 2 by springs 8 and a package 10 to be tested is tested on the plate 7. Consequently, fixtures need not be manufactured individually and pin positions are easily changed, so this fixture is usable for the test of an experimental package.

COPYRIGHT: (C)1987,JPO&Japio